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**PROCEEDINGS**

# Dielectric properties of TiO<sub>2</sub> co-doped with yttrium and niobium

Eliana Navarro dos Santos Muccillo<sup>1</sup>, Deborah Yohana Bertoldo da Silva<sup>1</sup>, Reginaldo Muccillo<sup>1</sup>

<sup>1</sup>Instituto de Pesquisas Energéticas e Nucleares

*e-mail: enavarro@usp.br*

The effects of small contents (up to 10 mol%) of Y<sub>2</sub>O<sub>3</sub> and Nb<sub>2</sub>O<sub>5</sub> on the microstructure and dielectric properties of TiO<sub>2</sub> were investigated, aiming to identify the underlying mechanism in the colossal permittivity of co-doped specimens. Sintered materials were prepared by the solid state reaction method and characterized by X-ray diffraction, scanning electron microscopy, and electrochemical impedance spectroscopy. All sintered specimens exhibited the characteristic tetragonal TiO<sub>2</sub> rutile phase. Secondary phases were detected at the grain boundaries, independent on the sintering temperature. The mean grain increased with both sintering temperature and co-dopants content. The higher electric permittivity was obtained for specimens with 5 mol% of co-dopants, sintered at 1480°C, and the lowest value of the dissipation factor for samples with 10 mol%, sintered at 1500°C. The dielectric properties of co-doped TiO<sub>2</sub> were attributed to the internal barrier layer capacitance and electron-pinned dipole defect mechanisms.

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